

## Notice of References Cited

Application/Control No.

09/686,304

Examiner

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Applicant(s)/Patent Under
Reexamination
DENT, PAUL W.

Art Unit
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## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
_	Α	US-6,690,739	02-2004	Mui, Shou Yee	375/265
	В	US-6,324,209	11-2001	Li et al.	375/146
	С	US-6,519,292	02-2003	Sakoda et al.	375/295
	D	US-5,923,711	07-1999	Willming, David A.	375/287
	E	US-5,636,251	06-1997	Citta et al.	375/341
	F	US-6,144,651	11-2000	Rinchiuso et al.	370/335
	G	US-6,449,002	09-2002	Markman et al.	348/21
	Н	US-6,421,395	07-2002	Wei, Lee-Fang	375/265
	ı	US-6,553,535	04-2003	Asada et al.	714/777
	J	US-6,205,130	03-2001	DeJaco, Andrew P.	370/335
	К	US-6,226,320	05-2001	Hakkinen et al.	375/225
	L	US-6,498,789	12-2002	Honda, Shoichiro	370/342
	М	US-6,307,840	10-2001	Wheatley et al.	370/252

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р					
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	R					
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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